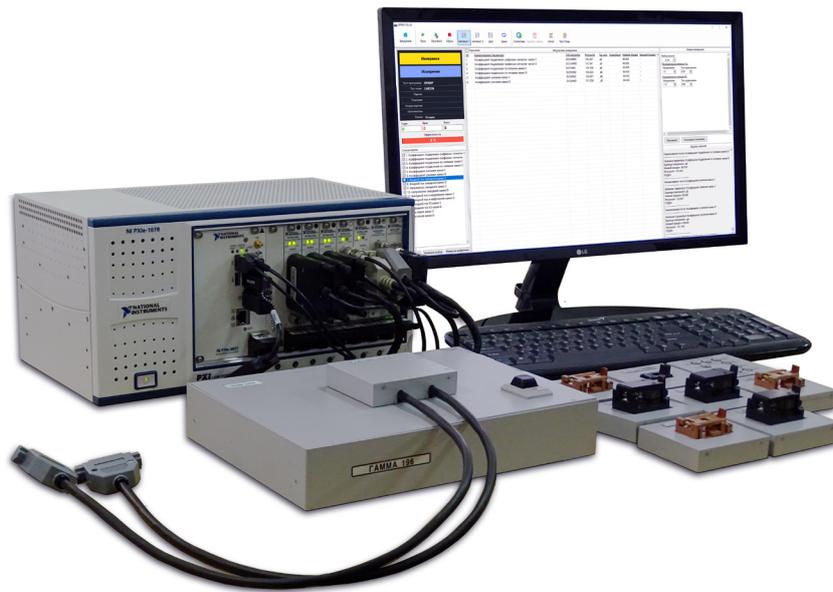


# High-Power PMIC Automated Testing System



## Overview

The system is designed for automated testing of linear and pulsing DC-to-DC voltage converters. It allows to perform high accuracy measurements of static and dynamic parameters of packaged and wafer level PMIC with up to 60 V and up to 10 A. The system is able to connect with various peripheral devices such as temperature chambers, handlers, probers etc.

## Applications

The automated test system can be used for validation, verification and characterization testing of packaged and wafer level high-power PMIC.

## Features

- Testing of PMIC parameters up to 60 V and 10 A
- High accuracy measurements
- Customizable hardware and software platform allowing to add new DUT's
- High reliable protection mechanisms for emergency cases
- Testing of wafer level and packaged PMICs
- Compatible with LabVIEW
- Compatible with testing automation software SINUS